https://doi.org/10.1017/S1551929515001273 Published online by Cambridge University Press

ProductNews

Navitar Introduces MicroMate 3X Zoom Lens

Navitar, Inc. announced the addition of the MicroMate 3X Zoom lens system to their extensive line of high-magnification lenses. The MicroMate was designed to capture and process four times as much data when compared to a traditional optical system. The system images onto a 4/3" sensor and retains the same pixel resolution across the entire field. The modular design and superb optical quality make it ideal for both industrial and life science applications.

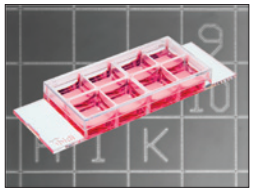
Navitar, Inc.
www.navitar.com

Aven Micro Lens System with Coaxial Illuminator is Ideal for Shiny Surfaces

Inspection and imaging of reflective surfaces present challenges that are overcome with Aven's new Micro Lens System microscope accessory, which features LED coaxial illumination to reduce glare and provide flat, even lighting without shadows across the full area of specimens with shiny surfaces. Field of view is 6 mm by 8 mm at low magnification (0.6×) and 0.8 mm by 1.2 mm at high magnification.

Aven, Inc.
www.aventools.com

ibidi Product News: ibidi µ-Slide 8 Plus Well Grid-500



ibidi now offers the µ-Slide 8 Well Grid-500, a chambered coverslip with eight 500 µm relocation grid. With this product, ibidi has combined two of its outstanding technologies: the µ-Slide 8 Well and the Grid-500—a laser-imprinted grid with a 500 µm repeat distance. This combination makes the new µ-Slide ideal for relocating and counting cells or cell clusters. The sample is observed through the polymer coverslip bottom.

ibidi GmbH
http://ibidi.com

New Helios G4 Series DualBeam from FEI

FEI announced the new Helios™ G4 DualBeam series, which offers the highest throughput ultra-thin TEM lamella preparation for leading-edge semiconductor manufacturing and failure analysis applications. The new Phoenix focused ion beam (FIB) makes finer cuts with higher precision and simplifies the creation of ultra-thin (sub 10 nm) lamella for transmission electron microscopy imaging. The FX is a flexible system that delivers <3Å STEM resolution. The HX model is geared specifically for high-throughput TEM lamella production.

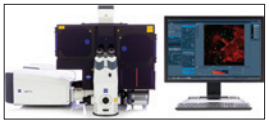
FEI Company
www.fei.com/helios-g4-fx-for-semiconductors

NEW Versatile High-Throughput SEM from JEOL

JEOL's new JSM-IT100 InTouchScope Series of Scanning Electron Microscopes. Featuring expanded EDS analysis capabilities and ports for multiple detectors, the InTouchScope can be configured to meet individual lab requirements at an exceptional value. It offers high-resolution imaging and a range of acceleration voltages at both high- and low-vacuum modes. Touchscreen operation or traditional keyboard and mouse interface are at the operator's fingertips. Fast data acquisition make imaging and analysis of samples a simple task.

JEOL USA, Inc.
www.jeolusa.com

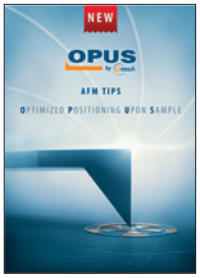
Olympus CKX53 Inverted Microscope



The Olympus CKX53 is an inverted microscope designed for fast, efficient cell culture checking and documentation. The CKX53 is built for workflow efficiency without sacrificing user comfort. All of the microscope controls are ergonomically located in the same area of the microscope for easy adjustments with minimal hand movement. The microscope is 20 percent lighter than previous models, so it can be moved as needed. The CKX53 has a small footprint and takes up minimal space.

Olympus Corporation
www.olympus-lifescience.com

MikroMasch® Introducing OPUS™ AFM Tips



The key feature of OPUS™ is AFM tip visibility: OPUS™ AFM tips are positioned exactly at the end of each cantilever at an angle of 90 degrees, which enables a precise tip positioning on the sample to be measured. OPUS™ tips are available on all standard cantilever types for all commonly used AFM applications, including high-speed scanning. OPUS™ AFM probes also offer all major coatings that are being used in AFM. Evaluation samples are free.

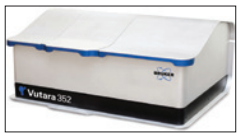
MikroMasch™, operated by Innovative Solutions Bulgaria Ltd.
www.opustips.com/en/contacts.html

AutoSIMS – Automatic Surface Analysis System

AutoSIMS represents the sum of a combination of instrument developments undertaken for a range of customers. The result is an easy-to-use, general-purpose laboratory tool that can undertake routine surface analysis measurements for product monitoring, failure analysis, and verification tasks. Based around the geometry of the Compact SIMS, the AutoSIMS brings a very high level of automation to surface analysis with a typical user training period of under a day.

Hiden Analytical
www.HidenAnalytical.com

Bruker Introduces Vutara 352 Super-Resolution Fluorescence Microscope



Bruker announced the first quantitative super-resolution microscope, the Vutara™ 352. The Vutara 352 offers speed, imaging depth, and resolution to deliver significant advantages over competing approaches, now also adding real-time quantitative capabilities. The Vutara 352 is now also compatible with Bruker's Opterra multi-point confocal microscope, creating a unique combination of super-resolution and confocal capabilities, where both instruments are designed for high-speed imaging. This enables the visualization of large-scale, high-resolution structural context correlated with super-resolution imaging.

Bruker Corporation
www.bruker.com

Bruker Introduces Ultima Investigator Microscope for *In-Vivo* Imaging

Bruker announced the release of the Ultima Investigator Multiphoton Microscope for high-performance *in-vivo* imaging. Up to four close-coupled detectors maximize collection efficiency and, when combined with Bruker's next-generation preamplifier, produce the signal-to-noise levels that enable high-speed imaging at depths up to 1 micron. Ultima Investigator also uses a rotatable nose piece that allows for the off-axis imaging required for advanced, *in-vivo* neural activity research.

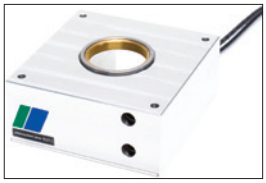
Bruker
www.bruker.com

Advanced Infrared Camera at an Affordable Price

Allied Vision has released a new entry-level Goldeye model for the short-wave infrared spectrum (SWIR), the Goldeye G-008 SWIR. Packed with all the features and benefits of the current Goldeye camera family, the new model for SWIR applications is equipped with a smaller resolution sensor. As a result, the price for the camera could be significantly reduced so that infrared imaging becomes affordable for many cost-sensitive applications.

Allied Vision
www.alliedvision.com

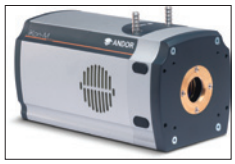
Objective Positioners for Industrial Applications



piezosystem introduced two new systems. The optical axis stays the same with the MIPOS 140. The position of the optical system remains unchanged after the installation, and the focal point continues to be at the desired adjusted position. The objective positioner MIPOS 250 SG has a travel range of 250 microns in open loop operation and 200 microns in closed loop. The positioner has been constructed to be screwed to a flat surface.

piezosystem jena
www.piezosystem.com

Andor Launches Enhanced Back-illuminated CCD



Andor Technology, an Oxford Instruments company, announced the launch of the iKon-M 912 back-illuminated CCD camera, offering the ultimate in high dynamic range and low noise performance. The 512 × 512 CCD array with 24 µm pixels has been optimized for extremely high well depth and maximum photon collection per pixel. An enhanced electronic design facilitates multiple readout speeds ranging from 50 kHz up to 5MHz, the latter facilitating fast frame rate usage or focusing.

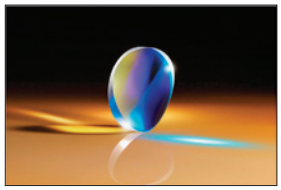
Andor Technology Ltd.
www.andor.com/ikon-m-912

JAI Expands its Spark Series with new CMOS 12-Megapixel Industrial Area Scan Camera

JAI announced that the company had expanded its Spark Series of high-performance industrial area scan cameras with two new models: Spark SP-12000C-CXP4 and Spark SP-12000M-CXP4 (color camera and monochrome camera, respectively). Both camera models are based on the CMOSIS 12-megapixel CMOS sensor (CMV12000) featuring a resolution of 4096 × 3072 pixels, 5.5 µm square pixels, and global shutter technology.

JAI Inc.
www.jai.com

TECHSPEC® Laser Line PCX Cylinder Lenses



Edmund Optics® introduced its new TECHSPEC® Laser Line PCX Cylinder Lenses. These versatile cylinder lenses are designed for applications that require light to be focused in only one direction, including light focused into a slit or line scan detector. TECHSPEC Laser Line PCX Cylinder Lenses are offered with a choice of multiple precision anti-reflective coatings for common wavelengths.

Edmund Optics®, Inc.
www.edmundoptics.com

Eliminate Eye Strain with Aven's Macro Vue HD Video Inspection Systems

Aven has created the Macro Vue HD Video Inspection System. The stand-alone high-magnification inspection system is designed to eliminate the fatigue commonly associated with frequent use of traditional microscopes. Featuring an adjustable front-mounted 10" LC HD monitor, and equipped with a wide range zoom lens with adjustable iris, zoom, and focus mounted to a durable standard stand, these innovative yet compact video inspection systems save precious space without sacrificing quality.

Aven Inc.
www.aventools.com